## Notice of References Cited Application/Control No. 10/801,733 Examiner Christopher P. Bruenjes Applicant(s)/Patent Under Reexamination FAY ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,309,456	10-2001	Anthony, Brian James	106/277
*	В	US-5,253,461	10-1993	Janoski et al.	52/408
*	С	US-2004/0166087	08-2004	Gembala, Henry	424/076.1
*	D	US-5,882,731	03-1999	Owens, Richard L.	427/353
*	E	US-2004/0014385	01-2004	Greaves et al.	442/148
*	F	US-2001/0009834	07-2001	Peng et al.	442/361
*	G	US-2005/0089653	04-2005	Shoshany et al.	428/034.1
	Н	US-	18		
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 57-032508 A	02-1982	Japan	Yabusaki et al	A01N 43/42
	0				(/	
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U /	/ Derwent English Abstract for DD 74314 A
	٧	
	8	·
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.